

EMC Society



Central Texas Section

Chapter Meeting

March 24, 2010

Austin, TX

IEEE

Agenda

- Chapter Meeting
 - Introduction
 - Chapter calendar
 - Section Planning Meeting
 - Current events
 - Future events
- Technical Presentation
- Wrap Up

Introductions

- Name
- Company or school
- Your connection to or interest in EMC

Introductions

- Chapter Leadership Team
 - Chair - Ross Carlton
National Instruments, ross.carlton@ni.com
 - Vice Chair - Mike Royer
Foxconn, mroyer@mikeroyer.com
 - Secretary/Treasurer - Mark Prchlik
Panashield, mark@prchlik.com

Chapter Calendar

● 2010 Technical Program

* EMCS Distinguished Lecturer
** EMCS Respected Speaker

Month	Topic
January	Design of a Medium Power RF Absorber by Mechanical Approach, Dr. Vince Rodriguez, ETS-Lindgren
February *	EMC/EMI Issues in Biomedical Engineering, Dr. Ji Chen, University of Houston
→ March	Standards Development: CISPR 32 and CISPR 35, Richard Worley, Dell
April	IEC 61000-4-2, -4, -5, -11 Standards Revisions , Tom Revesz, HV Technologies
May **	<i>Topic TBD</i> , Elya Joffe, KTM Project Engineering (Outgoing EMCS President)
June	
July	2010 IEEE EMC Symposium, Ft. Lauderdale, FL
August	<i>Topic TBD</i> , Bob Scully, NASA
September	EMI/EMC Simulation and Modeling, David Johns, VP Engineering, CST
October *	Metamaterials for EMC Engineers, Omar Ramahi, Univ. of Waterloo
November	
December	

Chapter Calendar

- 2010 Administrative Activities
 - March
 - Chapter Chairs lunch
 - April
 - Call for 2011 officer nominations
 - May
 - Close nominations

CTS Chapter Chair Lunch

- CTS Chapter Chair Lunch
 - Met with CTS officers and local Chapter chairs
 - Discussed
 - E-Week activities in 2011
 - CTS ExCom meeting minutes
 - IEEE USA conference
 - Chapter conference plans
 - Chapter issues

Future Events

International Instrumentation & Measurement Technology Conference



- May 2-6, 2010
- Hilton, Austin, TX
- imtc.ieee-ims.org

Future Events

2010 IEEE EMC Symposium

July 25-30, 2010, Convention Center, Ft. Lauderdale, FL



- Update
 - Technical papers reviews in process
 - Advance Program
 - In preparation. Will come out in late April
 - Conference hotels are filling up
 - Make your reservations now!
 - Experiment & Demo proposals due by 4/30

Future Events

2010 IEEE EMC Symposium

July 25-30, 2010, Convention Center, Ft. Lauderdale, FL

- **Workshops & Tutorials**



Monday

Fundamentals of EMC

Practical Radiated Measurements using Antennas and Field Probe

Power Quality and Low-Frequency EMC in Electrical Systems

ESD and Lightning Testing Additions to MIL-STD-461G

Introduction to EMI modeling techniques

All about EMI above 1 GHz

How to simplify real-world complex systems into realistic, solvable, accurate models

Application of Reverberation Chambers

Future Events

2010 IEEE EMC Symposium

July 25-30, 2010, Convention Center, Ft. Lauderdale, FL



- ## Workshops & Tutorials

Friday

EMC Leadership

Application of Time Domain Measurements for Test Site Validation and Antenna Calibration

EMC Society History

Fundamentals of Signal Integrity

Emissions and Immunity near field scanning techniques

Basic EMC Measurements

Capturing the Electromagnetic Environment

EM Field Coupling with Transmission Lines, from Classical Theory to Recent Enhancements

Practical Tips on 17025 Compliance

Future Events

2010 IEEE EMC Symposium

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- **Special Sessions**



Tuesday, Wednesday & Thursday

Multi-Gbps Interconnect Simulation and Measurement for Signal Integrity and EMI
Requested afternoon session.

EMI Information Leakage

Modeling/Simulation Validation Standards and Applying the FSV Technique to Quantify
Validation Quality

Nanomaterials and Nanodevices for EMC Applications

Hybrid Techniques for EMC Analysis of Complex Systems

Evolving Trends in Spectrum Management and Engineering

Technical Presentation

EMC Standards Development: CISPR 32 and CISPR 35

New EMI Requirements for Multimedia Equipment

by Richard Worley
Sr. Regulatory Engineer
Dell

Wrap-Up

See You Next Time?

Wednesday, April 21, 2010

Tom Revesz of HV Technologies will present on the most significant recent changes to the basic conducted transient immunity test standards applicable to CE Mark Testing; IEC 61000-4-2, -4, -5, -11 for ESD, EFT, SURGE, and VD&I as they evolve from Edition 1 to Edition 2.